

Detecting Similar Code Segments through Side Channel Leakage in Microcontrollers

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Germany

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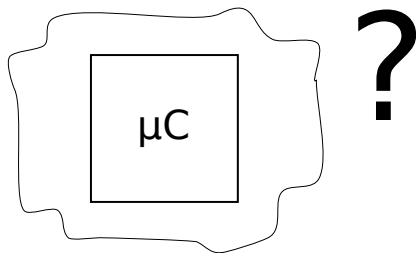
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University of Applied Sciences

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BOCHUM

RUB

Motivation: Software Plagiarism in Microcontrollers

- ▶ A product comes to the market with the same capabilities
- ▶ *Does the system contain our intellectual property?*



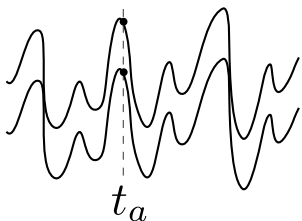
- ▶ Adversary takes our binary
- ▶ Effective read-out protection
- ▶ Comparison of code binaries not possible
- ▶ *Our solution:* compare power side channel leakage of the two implementations

Observations about the Power Side Channel

Varying inputs

Input = x_1
⋮
Input = x_n

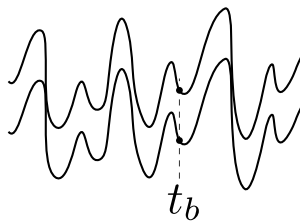
Power traces of program 1



samples from all traces at time t_a



Power traces of program 2



samples from all traces at time t_b



- ▶ high correlation when same data is processed
- ▶ low correlation when different data is processed

Our Approach

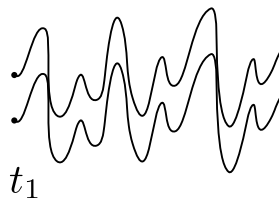
Varying inputs

I_1
 \vdots
 I_n

Power traces of program 1



Power traces of program 2



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$



Our Approach

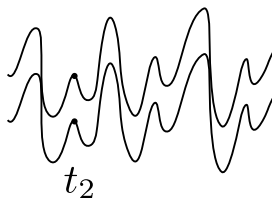
Varying
inputs

I_1
 \vdots
 I_n

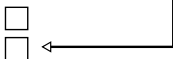
Power traces of
program 1



Power traces of
program 2



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$



Our Approach

Varying inputs

I_1
 \vdots
 I_n

Power traces of program 1



Power traces of program 2



t_1



t_{M_2}



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$

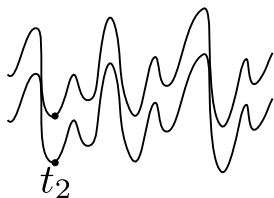


Our Approach

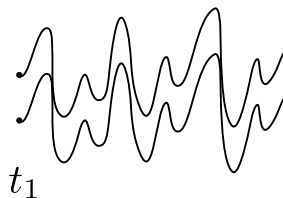
Varying
inputs

I_1
 \vdots
 I_n

Power traces of
program 1



Power traces of
program 2



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$

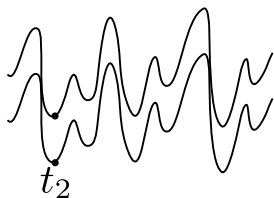


Our Approach

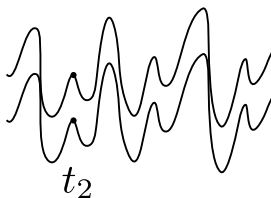
Varying
inputs

I_1
 \vdots
 I_n

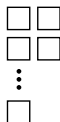
Power traces of
program 1



Power traces of
program 2



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$

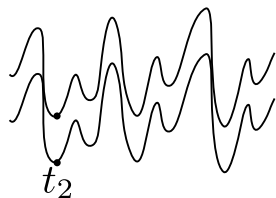


Our Approach

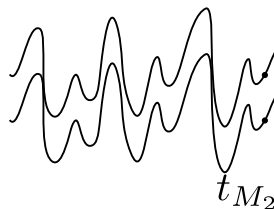
Varying inputs

I_1
 \vdots
 I_n

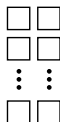
Power traces of program 1



Power traces of program 2



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$



Our Approach

Varying
inputs

I_1
 \vdots
 I_n

Power traces of
program 1



Power traces of
program 2



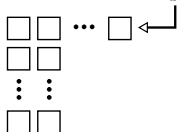
t_{M_1}



t_1



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$



Our Approach

Varying inputs

I_1
 \vdots
 I_n

Power traces of program 1



Power traces of program 2



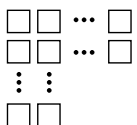
t_{M_1}



t_2



$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$



Our Approach: Correlate at all Times

Varying inputs

I_1
 \vdots
 I_n

Power traces of program 1



t_{M_1}



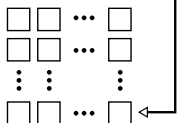
Power traces of program 2



t_{M_2}



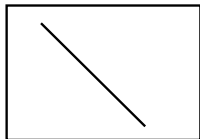
$$\hat{\rho}(\mathbf{x}, \mathbf{y}) = \frac{\sum_{i=1}^N (x_i - \hat{x})(y_i - \hat{y})}{\hat{\sigma}_x \hat{\sigma}_y}$$



Expectations about the Similarity Matrix

- ▶ The similarity matrix shows at what time similar computations happen

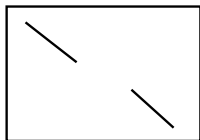
Identical program,
identical data



Similar program,
similar data



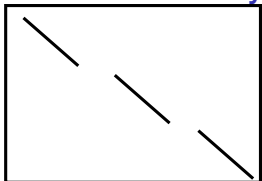
Partially identical program,
identical data



Different program
or
different data



Our Approach: Similarity measure

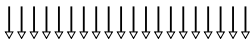


Suspicious program

Genuine program

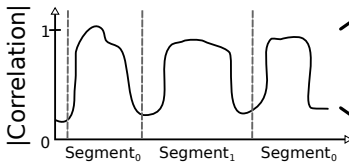


$\text{abs}(\max(\text{col}_i))$



$$\rho_{col} = \frac{1}{M_1} \sum_{i=1}^{M_1} p_{col_i}$$

Global similarity measure



$$\rho_{Seg_0} = \frac{1}{|Seg_0| * N_0} \sum_i^{|Seg_0| * N_0} p_{col_i}$$

$$\rho_{Seg_1} = \frac{1}{|Seg_1| * N_1} \sum_i^{|Seg_1| * N_1} p_{col_i}$$

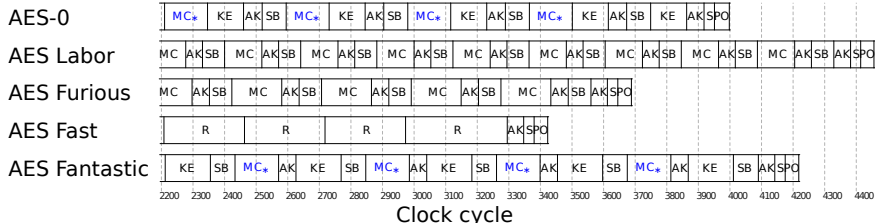
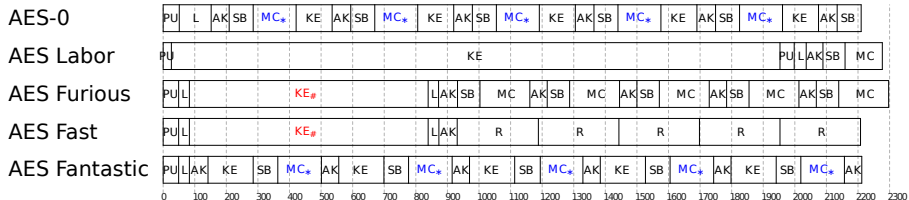
Local similarity measure

Experimental Setup

- ▶ Smartcards with ATmega163 microcontroller
 - ▶ 8-bit μC , running at 4MHz
- ▶ Measure using a digital oscilloscope (PicoScope 6402C)
 - ▶ sampling rate is 375 MHz



Test Programs: Implementations of AES in Assembly



PU - push registers
 PO - pop registers
 *,# - identical code

L - load key/plaintext
 S - store ciphertext

KE - key expansion
 AK - add round key

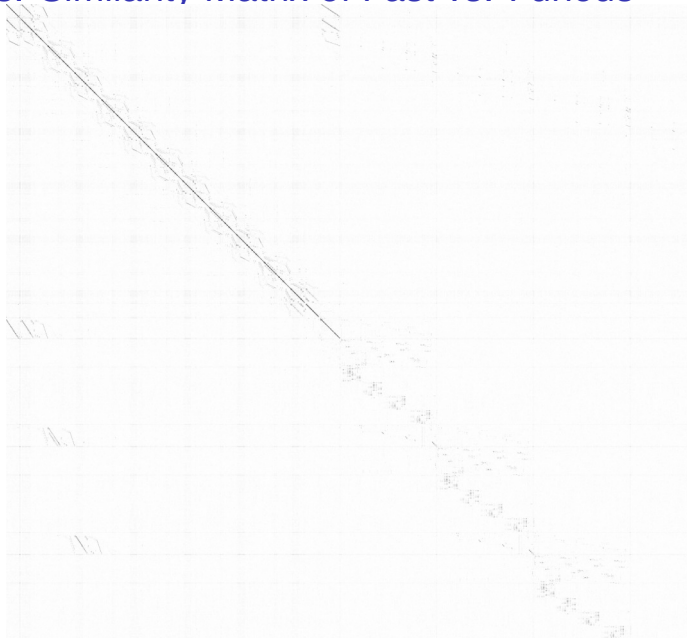
SB - shift rows and subbytes
 MC - mix columns
 R - one AES round in Fast

- ▶ 10k traces were recorded for each implementation

Results: Similarity Matrix of Furious vs. Furious

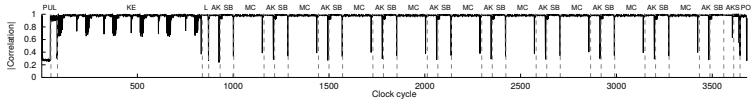


Results: Similarity Matrix of Fast vs. Furious

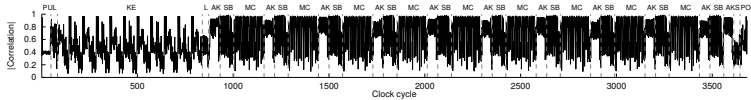


Results: Maximum Projection into Furious

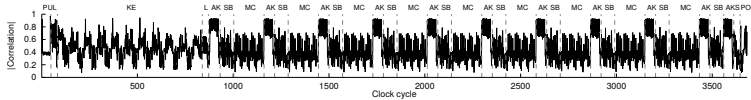
Furious in Furious



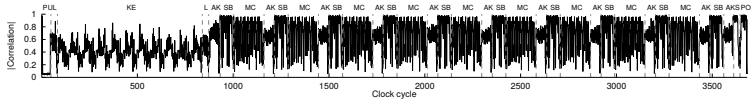
AES-0 in Furious



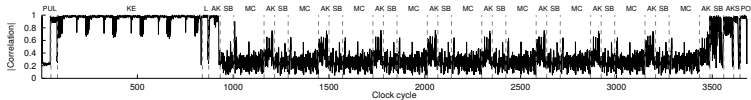
AES Labor in Furious



Fantastic in Furious



Fast in Furious



PUL - push registers
PO - pop registers

L - load key/plaintext
S - store ciphertext

KE - key expansion
AK - add round key

SB - shift rows and subbytes
MC - mix columns

Results: Maximum Projection, Global Similarity

	AES-0	AES Labor	Furious	Fast	Fantastic
AES-0	0.97	0.41	0.63	0.33	0.53
AES Labor	0.42	0.91	0.46	0.29	0.39
Furious	0.61	0.44	0.96	0.45	0.54
Fast	0.35	0.32	0.46	0.96	0.29
Fantastic	0.58	0.40	0.62	0.30	0.93

Results: Maximum Projection of Code Segments

	AK SB MC KE	AK SB MC KE	AK SB MC KE
AES-0	0.96 0.97 0.98 0.97	0.68 0.31 0.38 0.40	0.71 0.65 0.71 0.46
AES Labor	0.64 0.33 0.36 0.43	0.96 0.97 0.96 0.88	0.75 0.40 0.37 0.45
Furious	0.68 0.65 0.73 0.46	0.73 0.38 0.40 0.41	0.95 0.98 0.98 0.96
Fast	0.45 0.31 0.26 0.44	0.48 0.24 0.19 0.39	0.47 0.31 0.27 0.95
Fantastic	0.64 0.58 0.75 0.41	0.62 0.31 0.37 0.43	0.65 0.72 0.68 0.41

(a) →AES-0 (b) →AES Labor (c) →Furious

	AK KE R	AK SB MC KE
AES-0	0.69 0.46 0.28	0.66 0.57 0.75 0.33
AES Labor	0.73 0.45 0.23	0.62 0.32 0.35 0.40
Furious	0.85 0.95 0.27	0.62 0.71 0.70 0.32
Fast	0.97 0.95 0.98	0.43 0.27 0.25 0.31
Fantastic	0.64 0.40 0.25	0.96 0.96 0.97 0.90

(d) →Fast (e) →Fantastic

Experiment Set #2: Furious vs. Modified Furious

- ▶ addr: change register and data addresses
- ▶ swap: change the order of instruction execution
- ▶ addr+swap
- ▶ dummy: add 792 NOP instruction randomly
- ▶ dummy smart: add 792 leakage-generating instructions
- ▶ dummy smart+addr+swap

Dummy Smart Explanation

- ▶ Assembly language macros applied to state registers randomly throughout the code

<p>① INC \reg DEC \reg</p> <p>④ PUSH \tmp LDI \tmp, \c EOR \reg, \tmp POP \tmp</p>	<p>② NEG \reg NEG \reg</p> <p>⑤ LDI ZL, 0x00 LPM \tmp, Z</p> <p>⑥ EOR \tmp, \tmp</p>	<p>③ ROL \reg ROR \reg</p>	<p>⑦ PUSH \reg1 PUSH \reg2 PUSH \reg3 EOR \reg1, \reg2 EOR \reg2, \reg3 EOR \reg3, \reg1 POP \reg3 POP \reg2 POP \reg1</p>	<p>⑧ MOV \tmp, \reg ;; <i>save register</i> LDI ZH, hi8(hd_temp) LDI ZL, lo8(hd_temp) LD \reg, z MOV \reg, \tmp ;; <i>restore register</i></p>
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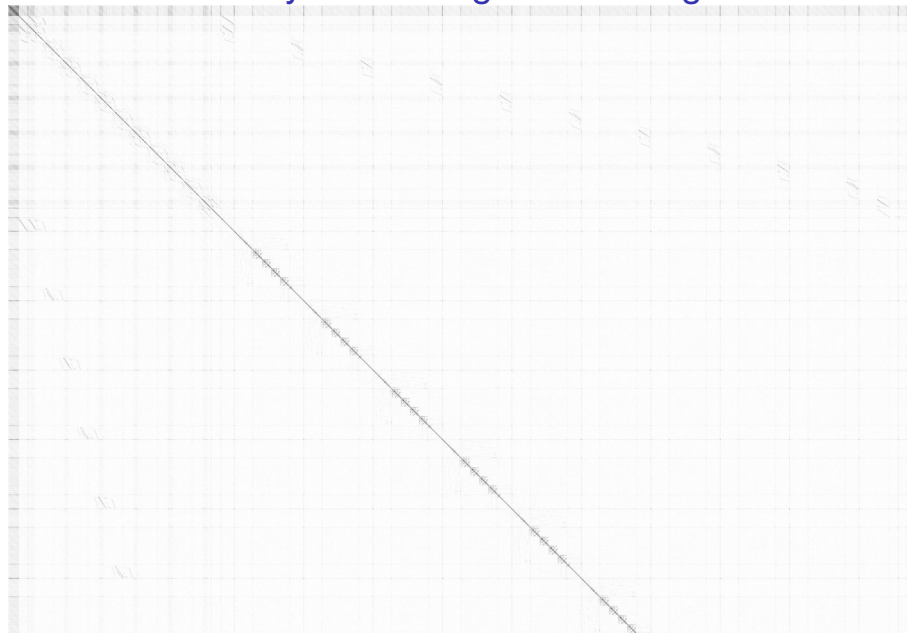
Results: Detection of Similar Code Segments

	genuine	AK	SB	MC	KE
genuine	0.96	0.95	0.98	0.98	0.96
addr	0.64	0.61	0.52	0.76	0.60
swap	0.73	0.84	0.62	0.78	0.80
addr+swap	0.52	0.59	0.37	0.64	0.45
dummy NOPs	0.84	0.92	0.72	0.87	0.86
dummy smart	0.83	0.82	0.75	0.85	0.85
dummy smart+addr+swap	0.51	0.54	0.36	0.63	0.44

(a) Global similarity

(b) Local similarity

Results: Similarity Matrix of genuine vs. genuine



Related Work

- ▶ (Becker et al. 2011)
 - ▶ Detect Hamming weight of the instructions
 - ▶ Embed watermarks detectable in the side channel
 - ▶ Problem: not all microcontrollers leak the Hamming weight of the instruction
- ▶ (Strobel et al. 2015)
 - ▶ Side channel disassembler
 - ▶ Use electromagnetic emanation
 - ▶ Detect individual instructions
 - ▶ Problem: Only tested on one microcontroller
- ▶ (Durvaux et al. 2012)
 - ▶ Use power consumption as its own watermark
 - ▶ Horizontal correlation one two traces
 - ▶ Problem: sensitive to the dummy cycles

Conclusions and Future Work

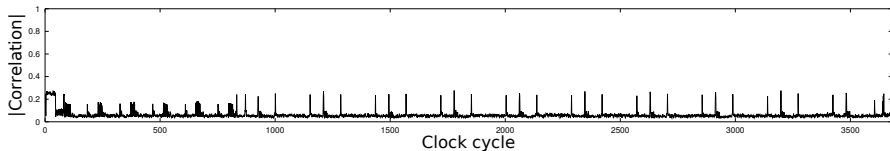
- ▶ Method for detecting similarity of programs using side channels
- ▶ We can detect identical code segments in the power consumption of a microcontroller
- ▶ Our method also works well with cases where many dummy cycles have been inserted
- ▶ Interesting application: detecting unlicensed implementations of patented technology

Future Work

- ▶ Combination of horizontal and vertical approaches
- ▶ Non-linear programs
 - ▶ dissect into data-dependent code paths
 - ▶ compute similarity for each code path
- ▶ Evaluation using different microcontrollers
- ▶ Dealing with random data

Questions?

Backup: Furious vs Furious Wrong Data



Backup: Visual Inspection

